





40V COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

Product Summary

Device	V _{(BR)DSS}	R _{DS(on)} max	I _D max (A) T _A = 25°C (Notes 3 & 5)
Q1	40V	25mΩ @ V _{GS} = 10V	7.5
	40 V	40mΩ @ V _{GS} = 4.5V	6.2
Q2	40)/	25mΩ @ V _{GS} = -10V	-7.3
	-40V	45mΩ @ V _{GS} = -4.5V	-5.7

Description and Applications

This MOSFET has been designed to ensure that R_{DS(on)} of N and P channel FET are matched to minimize losses in both arms of the bridge. The DMC4040SSD is optimized for use in 3 phases brushless DC motor circuits (BLDC), CCFL backlighting.

- 3 phases BLDC motor
- CCFL backlighting

Features and Benefits

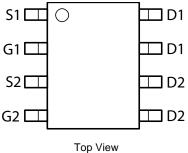
- Matched N & P R_{DS(on)} Minimizes power losses
- Fast switching Minimizes switching losses
- Dual device Reduces PCB area
- "Green" component and RoHS compliant (Note 1)
- Qualified to AEC-Q101 Standards for High Reliability

Mechanical Data

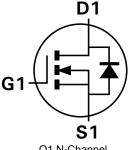
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0 (Note 1)
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish Matte Tin annealed over Copper lead frame. Solderable per MIL-STD-202, Method 208
- Weight: 0.074 grams (approximate)











Equivalent Circuit

D2 G2 S2 Q1 N-Channel Q2 P-Channel

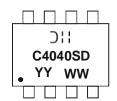
Ordering Information (Note 1)

Product	Marking	Reel size (inches)	Tape width (mm)	Quantity per reel
DMC4040SSD-13	C4040SD	13	12	2,500

1. Diodes, Inc. defines "Green" products as those which are RoHS compliant and contain no halogens or antimony compounds; further information about Diodes Inc.'s "Green" Policy can be found on our website. For packaging details, go to our website.

Marking Information

Note:



⊃∷ = Manufacturer's Marking C4040SD = Product Type Marking Code YYWW = Date Code Marking YY = Year (ex: 10 = 2010)WW = Week (01 - 53)





Maximum Ratings @T_A = 25°C unless otherwise specified

	Symbol	N-Channel - Q1	P-Channel - Q2	Unit		
Drain-Source Voltage	Drain-Source Voltage			40	-40	
Gate-Source Voltage	Gate-Source Voltage			±20	±20	1 V
Continuous Drain Current V _{GS} = 10 ^t		(Notes 3 & 5)		7.5	-7.5	
	V _{GS} = 10V	$T_A = 70^{\circ}C \text{ (Notes 3 \& 5)}$	l _D	5.8	-5.8	
		(Notes 2 & 5)		5.7	-5.7	
		(Notes 2 & 6)		6.8	-6.8	Α
Pulsed Drain Current	$V_{GS} = 10V$	(Notes 4 & 5)	I _{DM}	29.0	-29.0	
Continuous Source Current (Body diode) (No		(Notes 3 & 5)	Is	3.0	-3.0	
Pulsed Source Current (Body diode) (Notes 4 & 5)		(Notes 4 & 5)	I _{SM}	29.0	-29.0	

Thermal Characteristics @TA = 25°C unless otherwise specified

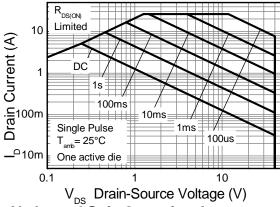
Characteristic	Symbol	N-Channel - Q1 P-Channel - Q2	Unit	
	(Notes 2 & 5)		1.25 10	
Power Dissipation Linear Derating Factor	(Notes 2 & 6)	P _D	1.8 14.3	W mW/°C
	(Notes 3 & 5)		2.14 17.2	
	(Notes 2 & 5)		100	
Thermal Resistance, Junction to Ambient	(Notes 2 & 6)	$R_{\theta JA}$	70	00/11/
	(Notes 3 & 5)		58	°C/W
Thermal Resistance, Junction to Lead	(Notes 5 & 7)	$R_{\theta JL}$	51	
Operating and Storage Temperature Range		$T_{J_i} T_{STG}$	-55 to +150	°C

Notes:

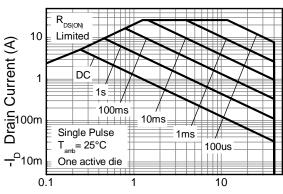
- 2. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
- 3. Same as note (2), except the device is measured at $t \le 10$ sec.
- Same as note (2), except the device is pulsed with D = 0.02 and pulse width 300μs.
 For a dual device with one active die.
- 6. For a device with two active die running at equal power.
- 7. Thermal resistance from junction to solder-point (at the end of the drain lead).



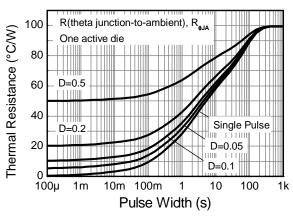
Thermal Characteristics



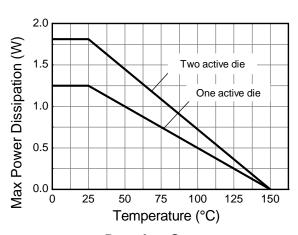
N-channel Safe Operating Area



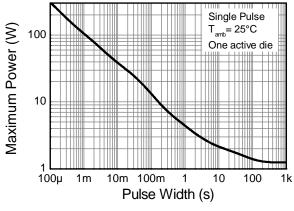
 ${}^{-}\mathrm{V}_{\scriptscriptstyle \mathrm{DS}}$ Drain-Source Voltage (V) **P-channel Safe Operating Area**



Transient Thermal Impedance



Derating Curve



Pulse Power Dissipation



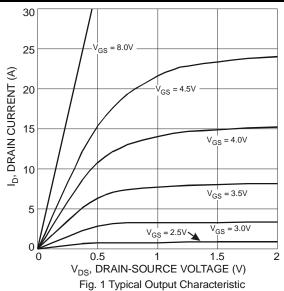
Electrical Characteristics - Q1 N-CHANNEL @TA = 25°C unless otherwise specified

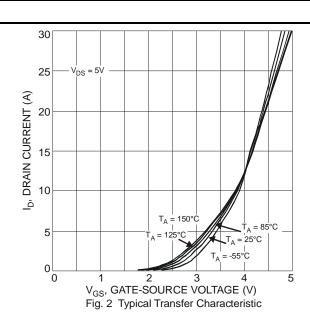
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	40	_	_	V	$I_D = 250 \mu A$, $V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1.0	μА	V _{DS} = 40V, V _{GS} = 0V	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS}=\pm20V$, $V_{DS}=0V$	
ON CHARACTERISTICS							
Gate Threshold Voltage	V _{GS(th)}	0.8	1.3	1.8	V	I _D = 250μA, V _{DS} = V _{GS}	
Static Drain Source On Registeres (Note 9)	7		0.013	0.025	Ω	V _{GS} = 10V, I _D = 3A	
Static Drain-Source On-Resistance (Note 8)	R _{DS} (ON)	_	0.028	0.040	1 12	V _{GS} = 4.5V, I _D = 3A	
Forward Transconductance (Notes 8 & 9)	g _{fs}	_	12.6	_	S	V_{DS} = 5V, I_D = 3A	
Diode Forward Voltage (Note 8)	V _{SD}	_	0.7	1.0	V	I _S = 1A, V _{GS} = 0V	
DYNAMIC CHARACTERISTICS (Note 9)							
Input Capacitance	C _{iss}	_	1790	_		V _{DS} = 20V, V _{GS} = 0V f= 1MHz	
Output Capacitance	Coss	_	160	_	pF		
Reverse Transfer Capacitance	C _{rss}	_	120	_			
Gate Resistance	R_g	_	1.03	_	Ω	V _{DS} = 0V, V _{GS} = 0V, f= 1MHz	
Total Gate Charge (Note 10)	Qg	_	16.0	_		V _{GS} = 4.5V	
Total Gate Charge (Note 10)	Qg	_	37.6	_		V _{DS} = 20V	
Gate-Source Charge (Note 10)	Qgs	_	7.8	_	nC	V _{GS} = 10V I _D = 3A	
Gate-Drain Charge (Note 10)	Q _{gd}	_	6.6	_			
Turn-On Delay Time (Note 10)	t _{D(on)}	_	8.1	_			
Turn-On Rise Time (Note 10)	t _r	_	15.1	_	200	V _{DD} = 20V, V _{GS} = 10V	
Turn-Off Delay Time (Note 10)	t _{D(off)}		24.3		ns	I _D = 3A	
Turn-Off Fall Time (Note 10)	t _f	_	5.3	_			

Notes:

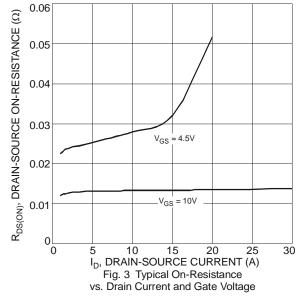
- 8. Measured under pulsed conditions. Pulse width $\leq 300 \mu s;$ duty cycle $\leq 2\%$
- 9. For design aid only, not subject to production testing.10. Switching characteristics are independent of operating junction temperatures.

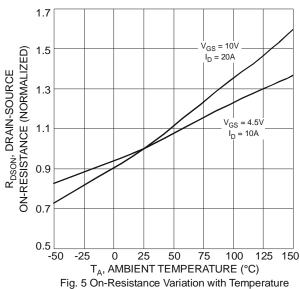
Typical Characteristics - Q1 N-Channel











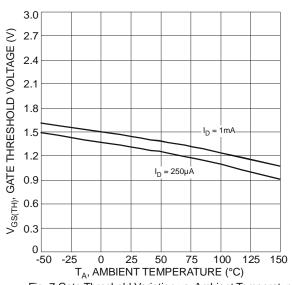


Fig. 7 Gate Threshold Variation vs. Ambient Temperature

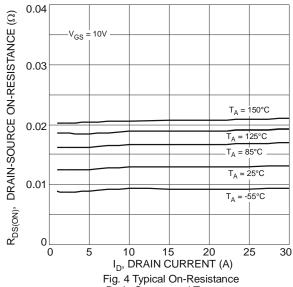


Fig. 4 Typical On-Resistance vs. Drain Current and Temperature

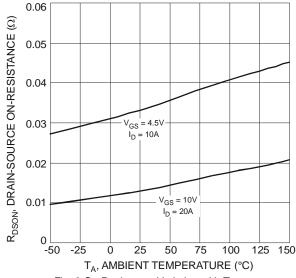
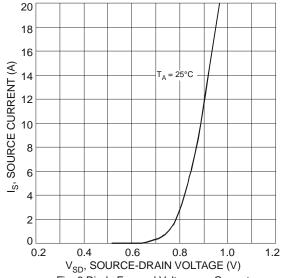
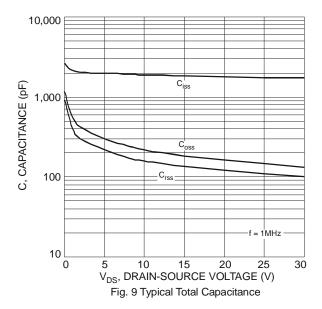
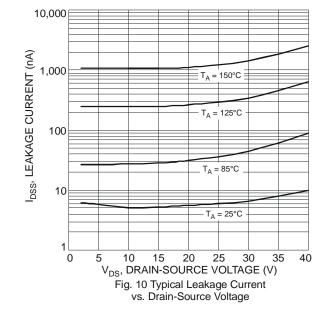


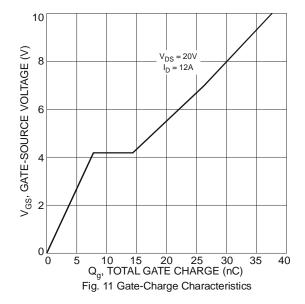
Fig. 6 On-Resistance Variation with Temperature













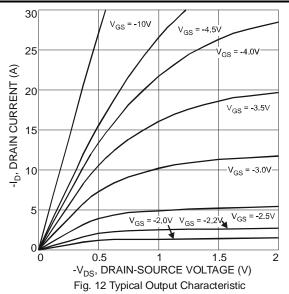
Electrical Characteristics - Q2 P-CHANNEL @TA = 25°C unless otherwise specified

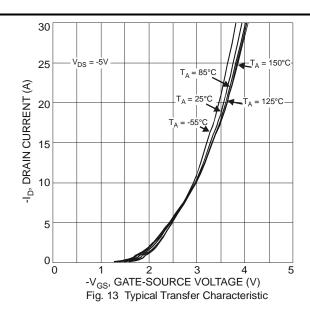
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	-40	_	_	V	$I_D = -250 \mu A, V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I _{DSS}	-	-	-1.0	μΑ	$V_{DS} = -40V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_	-	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS						•	
Gate Threshold Voltage	V _{GS(th)}	-0.8	-1.3	-1.8	V	$I_D = -250 \mu A, V_{DS} = V_{GS}$	
Static Drain Source On Registeres (Note 11)		-	0.018	0.025	Ω	$V_{GS} = -10V, I_D = -3A$	
Static Drain-Source On-Resistance (Note 11)	R _{DS(on)}		0.030	0.045	1 12	$V_{GS} = -4.5V, I_D = -3A$	
Forward Transconductance (Notes 11 & 12)	g fs	_	16.6	_	S	$V_{DS} = -5V, I_{D} = -3A$	
Diode Forward Voltage (Note 11)	V _{SD}	-	-0.7	-1.0	V	$I_S = -1A, V_{GS} = 0V$	
DYNAMIC CHARACTERISTICS (Note 12)						•	
Input Capacitance	C _{iss}	_	1643	_	pF	V _{DS} = -20V, V _{GS} = 0V f = 1MHz	
Output Capacitance	Coss	-	179	_			
Reverse Transfer Capacitance	C _{rss}	_	128	_			
Gate Resistance	Rg	_	6.43	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge (Note 13)	Qg	_	14.0	_		V _{GS} = -4.5V	
Total Gate Charge (Note 13)	Qg	_	33.7	_	nC	V _{DS} = -20V	
Gate-Source Charge (Note 13)	Q _{gs}	_	5.5	_	nc nc	$V_{GS} = -10V$ $I_D = -3A$	
Gate-Drain Charge (Note 13)	Q _{gd}	_	7.3	_			
Turn-On Delay Time (Note 13)	t _{D(on)}	-	6.9	_			
Turn-On Rise Time (Note 13)	tr	_	14.7	_		$V_{DD} = -20V, V_{GS} = -10V$	
Turn-Off Delay Time (Note 13)	t _{D(off)}	-	53.7	_	ns	$I_D = -3A$	
Turn-Off Fall Time (Note 13)	t _f	_	30.9	_			

Notes:

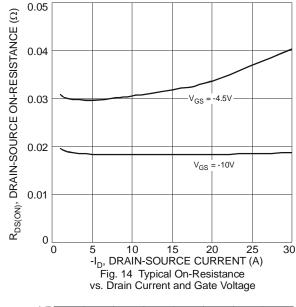
- 11.Measured under pulsed conditions. Pulse width $\leq 300 \mu s;$ duty cycle $\leq 2\%$
- 12. For design aid only, not subject to production testing.13. Switching characteristics are independent of operating junction temperatures.

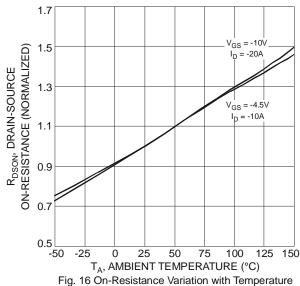
Typical Characteristics - Q2 P-Channel











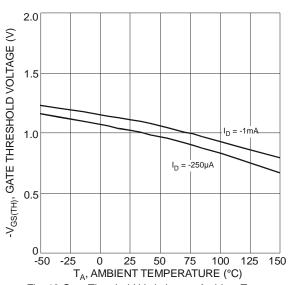
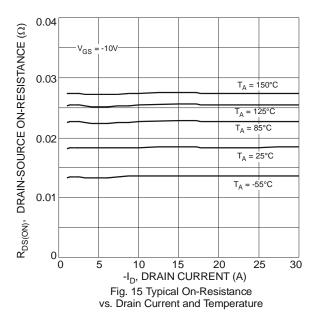


Fig. 18 Gate Threshold Variation vs. Ambient Temperature



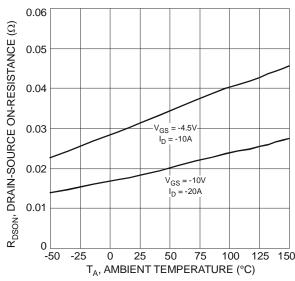


Fig. 17 On-Resistance Variation with Temperature

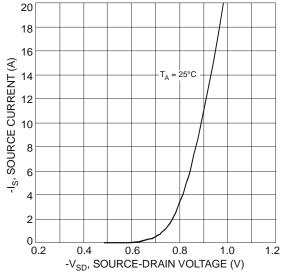
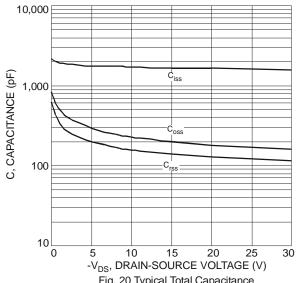
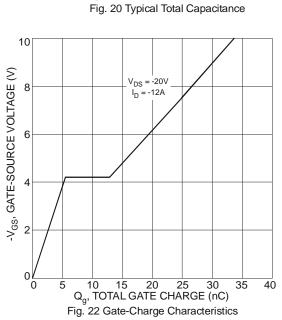
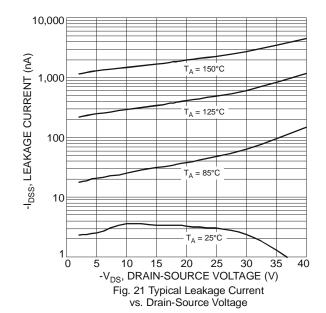


Fig. 19 Diode Forward Voltage vs. Current



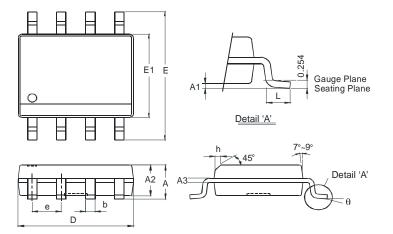






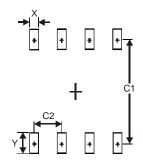


Package Outline Dimensions



SO-8					
Dim	Min	Max			
Α	•	1.75			
A1	0.10	0.20			
A2	1.30	1.50			
A3	0.15	0.25			
b	0.3	0.5			
D	4.85	4.95			
Е	5.90	6.10			
E1	3.85	3.95			
е	1.27 Typ				
h	•	0.35			
L	0.62	0.82			
θ	0°	8°			
All Dimensions in mm					

Suggested Pad Layout



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27





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 - 2. support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in significant injury to the user.
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